

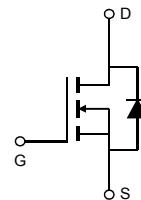


HUIZHOU JINSANE ELECTRONICS CO., LTD

AO4264

60V N-Channel AlphaMOS

General Description	Product Summary
<ul style="list-style-type: none">Trench Power AlphaMOS (αMOS MV) technologyLow $R_{DS(ON)}$Low Gate ChargeOptimized for fast-switching applications	V_{DS} 60V I_D (at $V_{GS}=10V$) 12A $R_{DS(ON)}$ (at $V_{GS}=10V$) < 11mΩ $R_{DS(ON)}$ (at $V_{GS}=4.5V$) < 13.5mΩ
Applications	100% UIS Tested 100% R_g Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AO4264	SO-8	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current <small>$T_A=25^\circ C$</small>	I_D	12	A
$T_A=70^\circ C$		9	
Pulsed Drain Current ^c	I_{DM}	48	
Avalanche Current ^c	I_{AS}	36	A
Avalanche energy <small>$L=0.1mH$</small> ^c	E_{AS}	65	mJ
V_{DS} Spike	10μs	V_{SPIKE}	V
Power Dissipation ^b	P_D	3.1	W
$T_A=70^\circ C$		2.0	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^a <small>$t \leq 10s$</small>	$R_{\theta JA}$	31	40	°C/W
Maximum Junction-to-Ambient ^{a,d} Steady-State		59	75	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	16	24	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.4	1.9	2.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=12\text{A}$ $T_J=125^\circ\text{C}$		9.2	11	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=10\text{A}$		15.6	19	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=12\text{A}$		50		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.72	1	V
I_S	Maximum Body-Diode Continuous Current				4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$		2007		pF
C_{oss}	Output Capacitance			177		pF
C_{rss}	Reverse Transfer Capacitance			12.5		pF
R_g	Gate resistance	$f=1\text{MHz}$	0.6	1.2	1.8	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=12\text{A}$		25.5	40	nC
$Q_g(4.5\text{V})$	Total Gate Charge			11	20	nC
Q_{gs}	Gate Source Charge			5.5		nC
Q_{gd}	Gate Drain Charge			2.5		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=1.25\Omega, R_{\text{GEN}}=3\Omega$		8.5		ns
t_r	Turn-On Rise Time			3.5		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			27		ns
t_f	Turn-Off Fall Time			3		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=12\text{A}, dI/dt=500\text{A}/\mu\text{s}$		15		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=12\text{A}, dI/dt=500\text{A}/\mu\text{s}$		55		nC

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

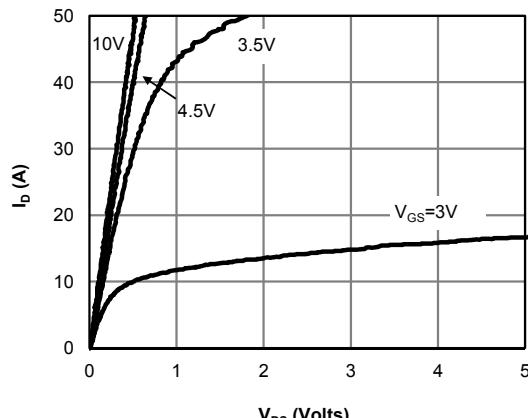


Figure 1: On-Region Characteristics (Note E)

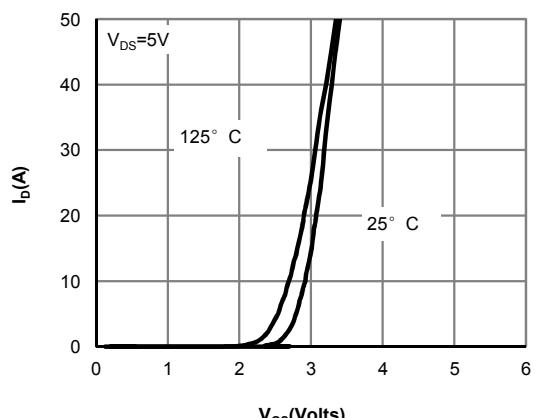


Figure 2: Transfer Characteristics (Note E)

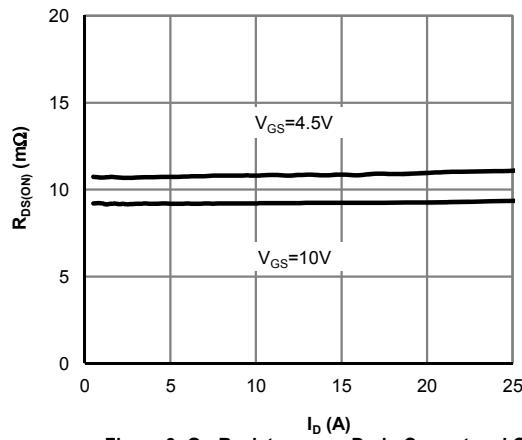


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

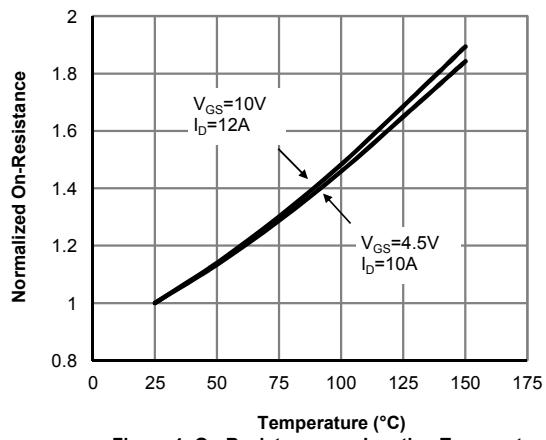


Figure 4: On-Resistance vs. Junction Temperature (Note E)

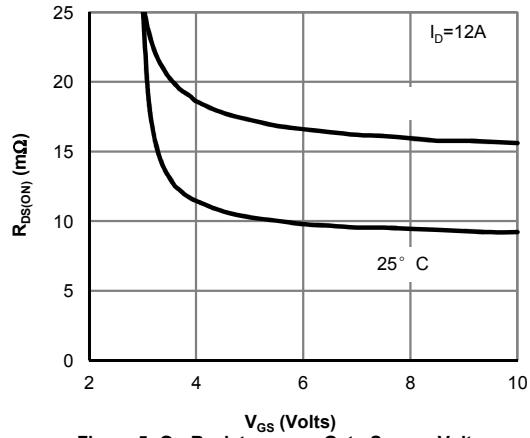


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

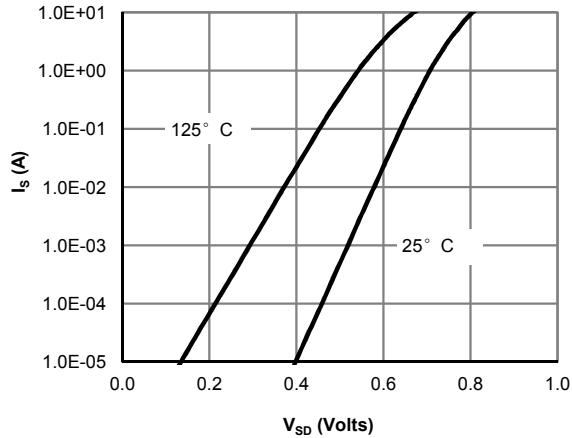


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

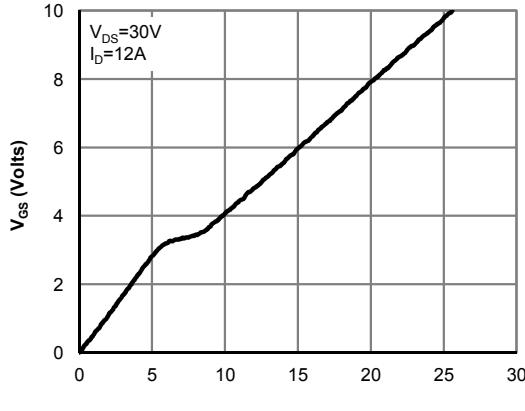


Figure 7: Gate-Charge Characteristics

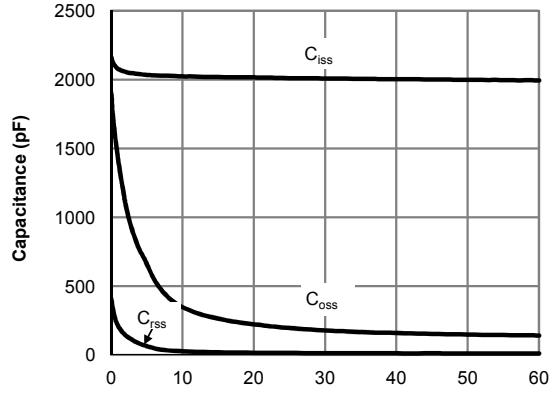


Figure 8: Capacitance Characteristics

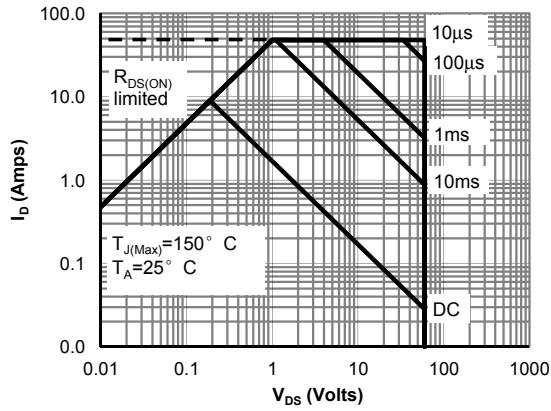


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

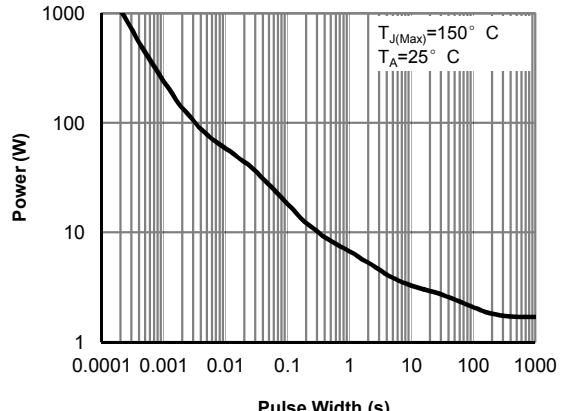


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

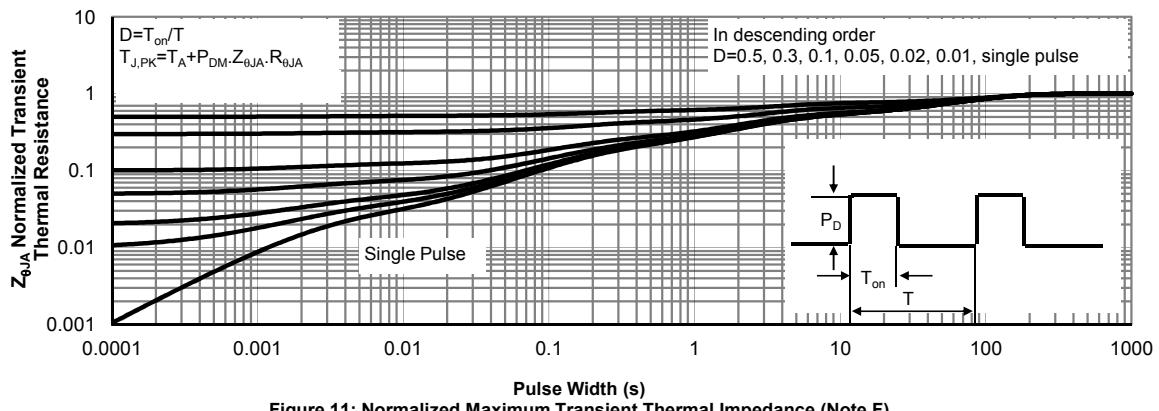
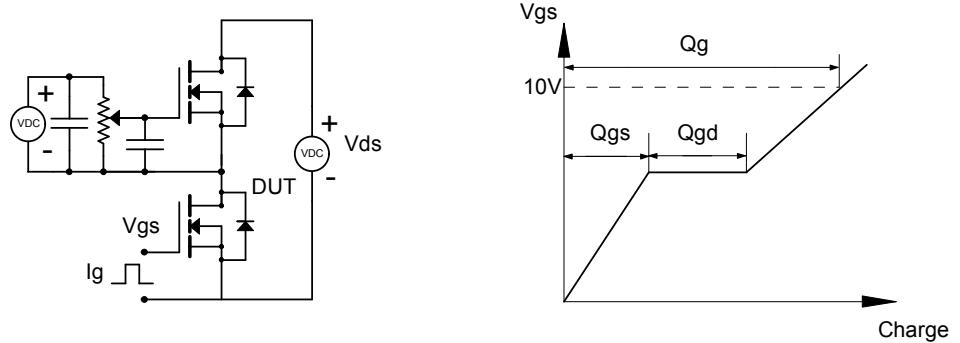
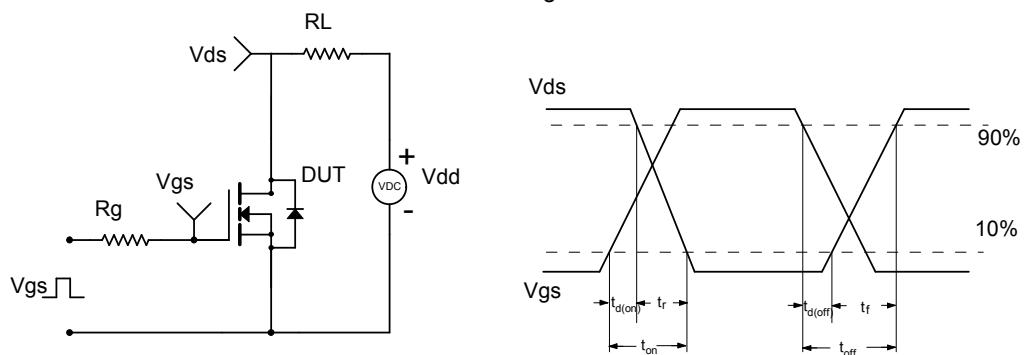


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

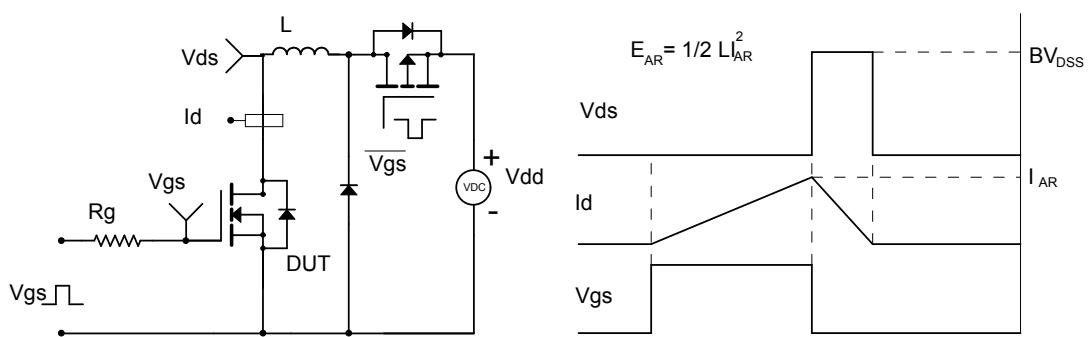
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

